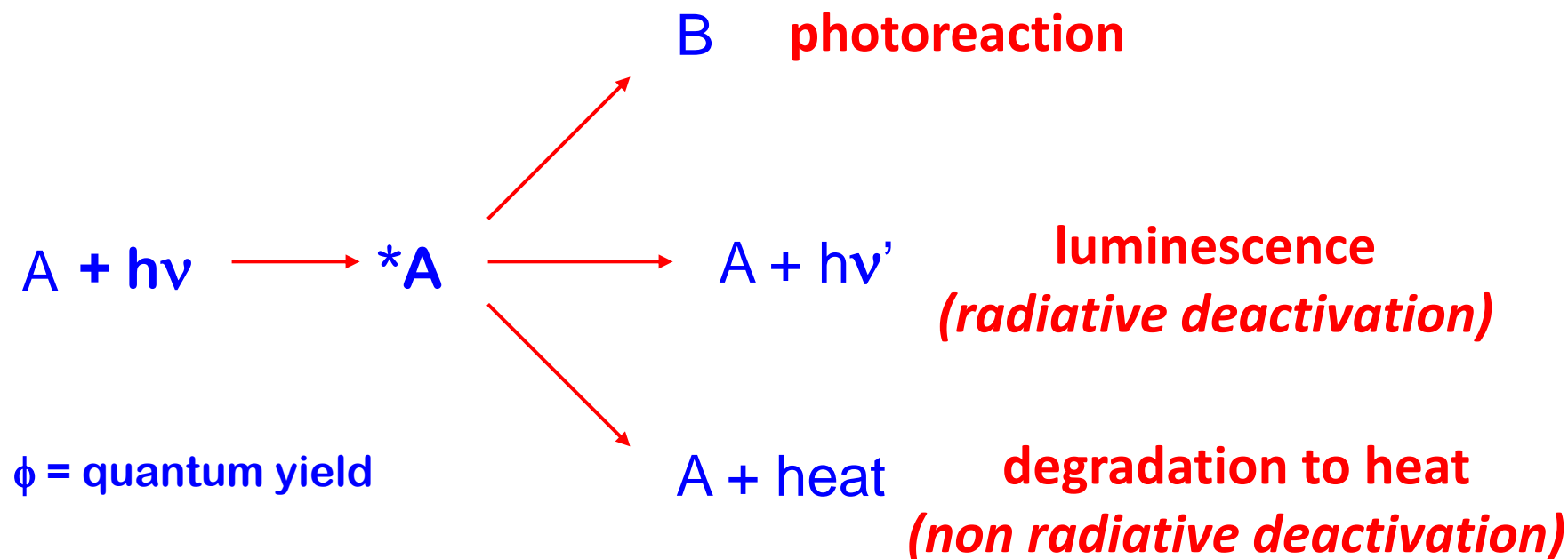


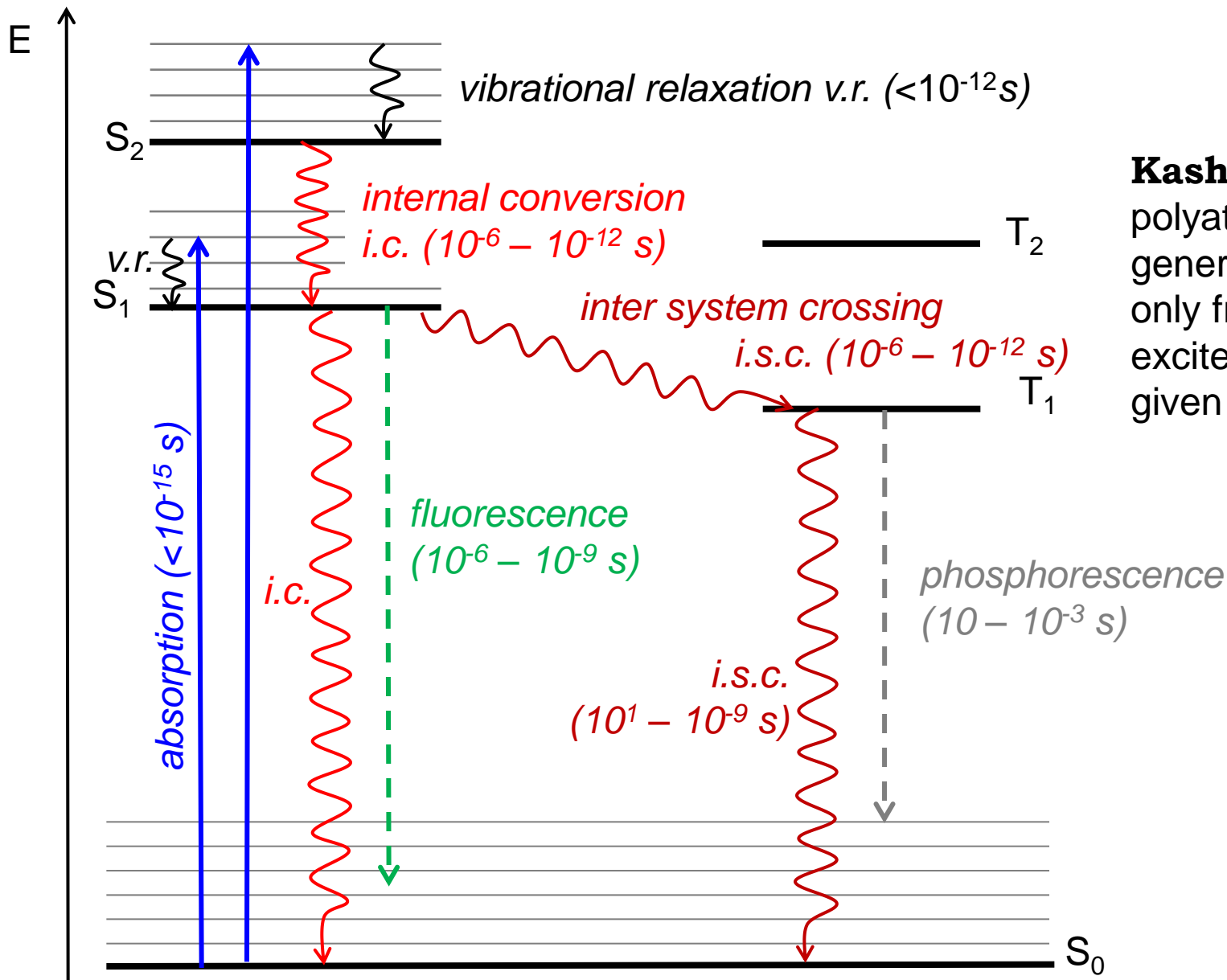
Photoluminescence spectroscopy

Excited state deactivation



$$\phi_{h\nu'} = \frac{\text{number of photons } h\nu' \text{ emitted}}{\text{number of photons } h\nu \text{ absorbed}}$$

Jablonski diagram: a typical organic molecule



Kasha's rule:

polyatomic molecules generally luminesce only from the lowest excited state of a given multiplicity

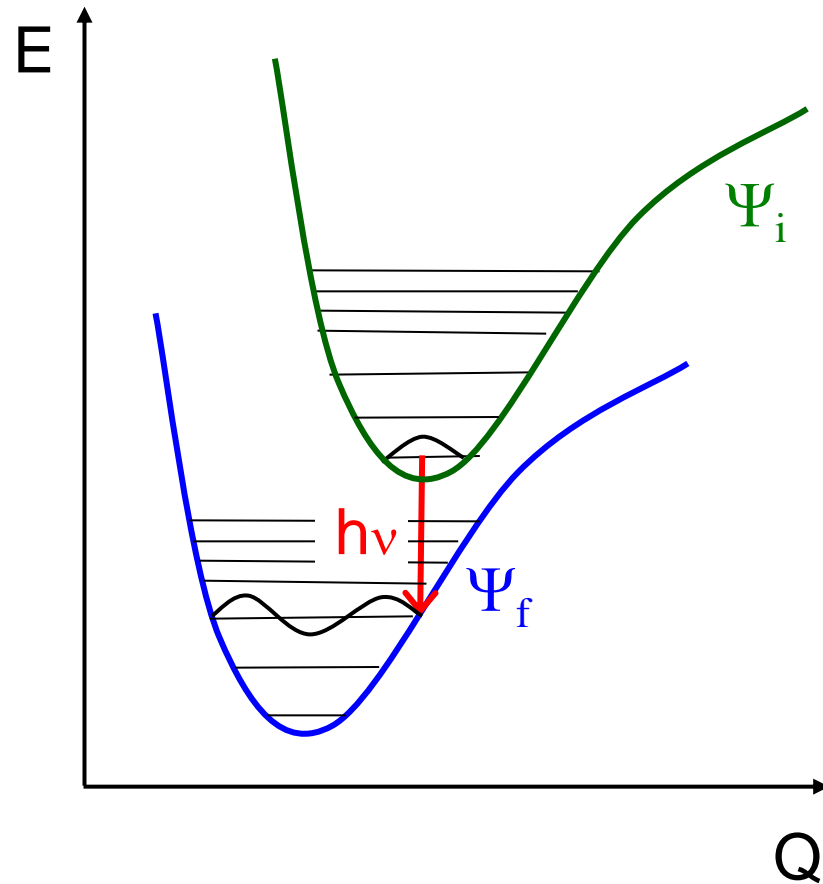
Radiative transitions

Spontaneous Emission

$$\Psi_i \rightarrow \Psi_f + h\nu$$

$$P_{\text{em}} \propto (\text{TM})^2 \nu^3$$

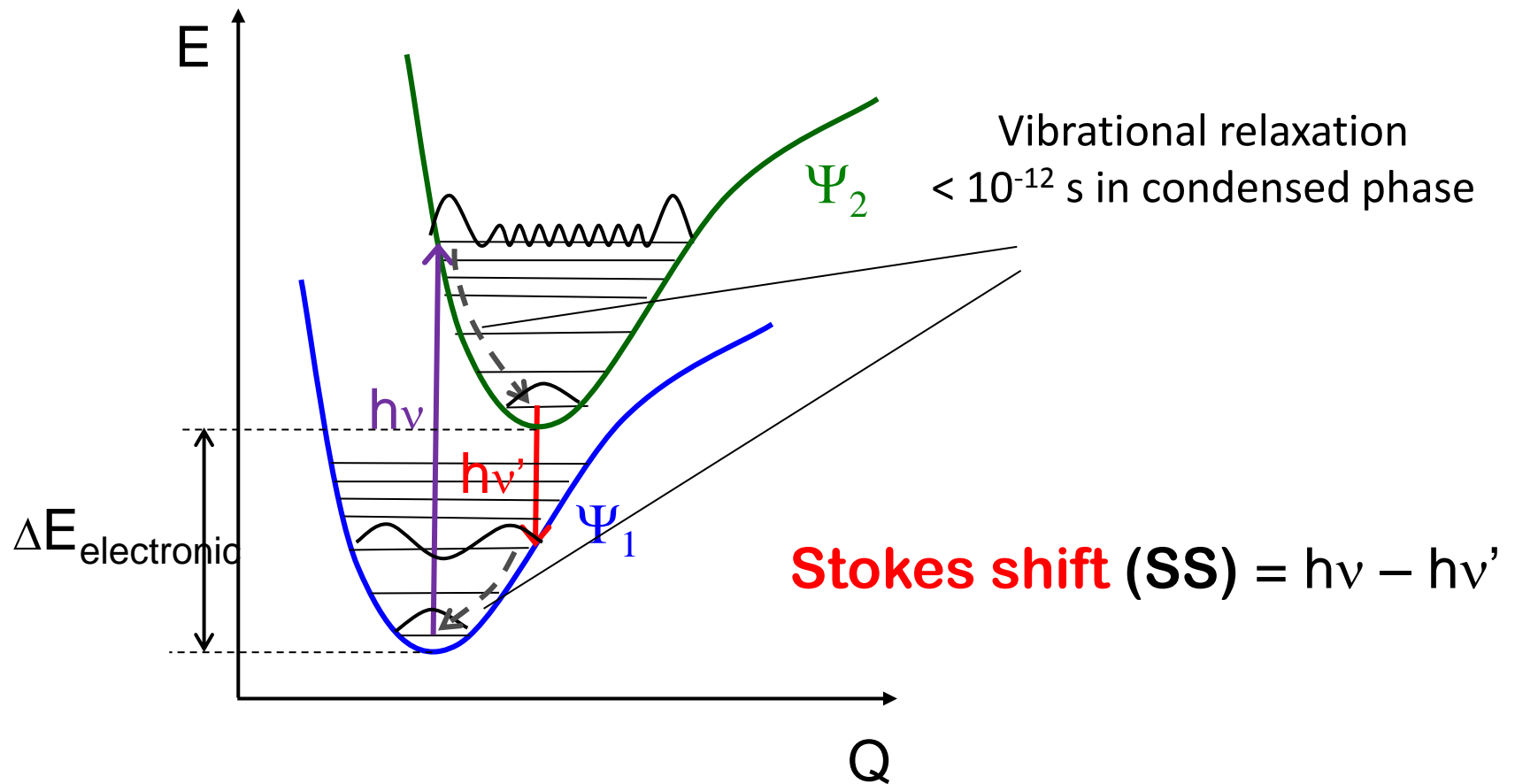
emission probability



fluorescence: spin-allowed radiative transition

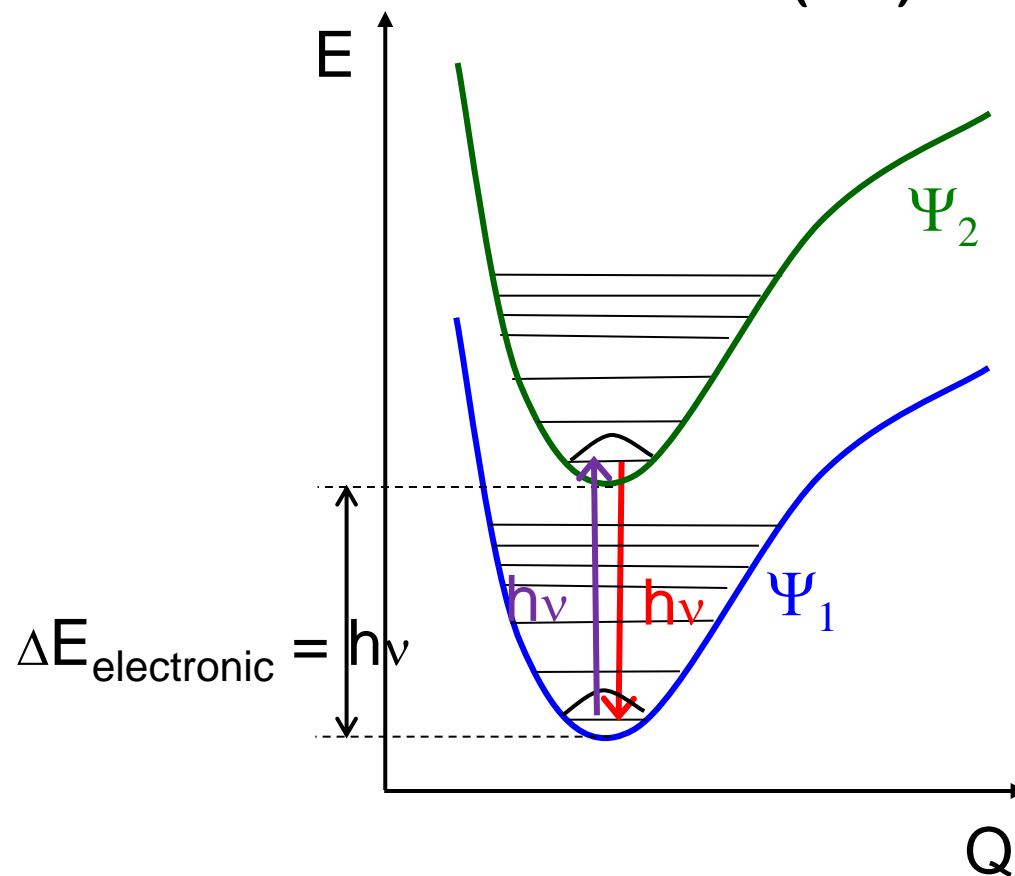
phosphorescence: spin-forbidden radiative transition

Excited state distortion

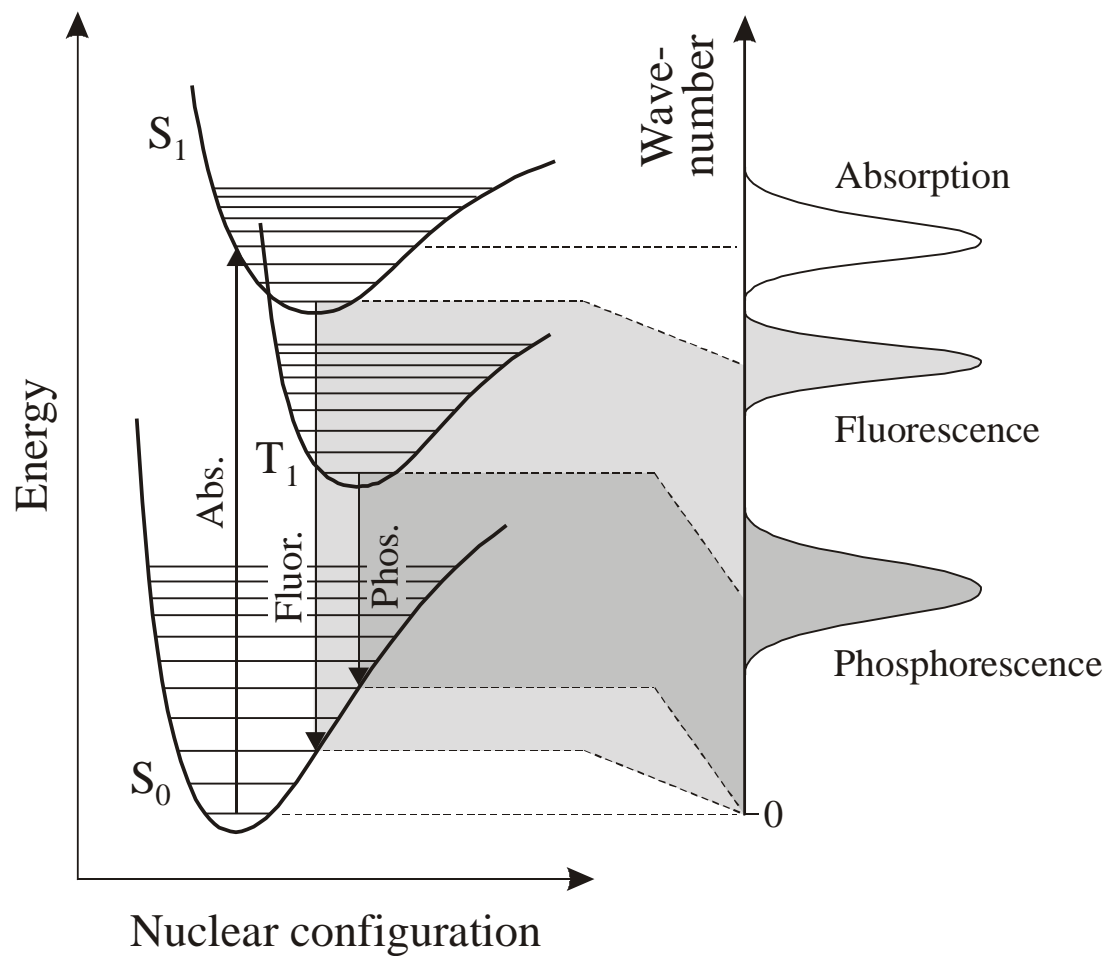


Zero-distorsion

Stokes shift (SS) = 0

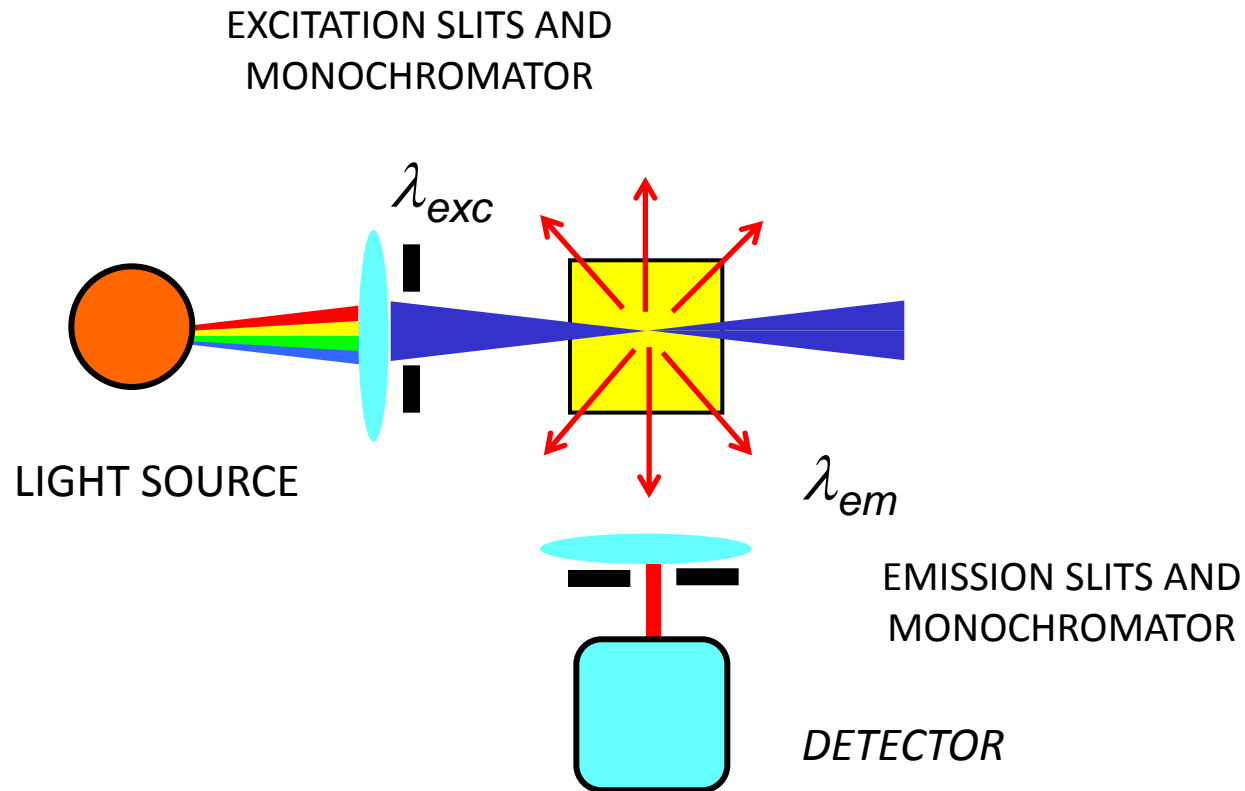


Absorption, fluorescence and phosphorescence bands



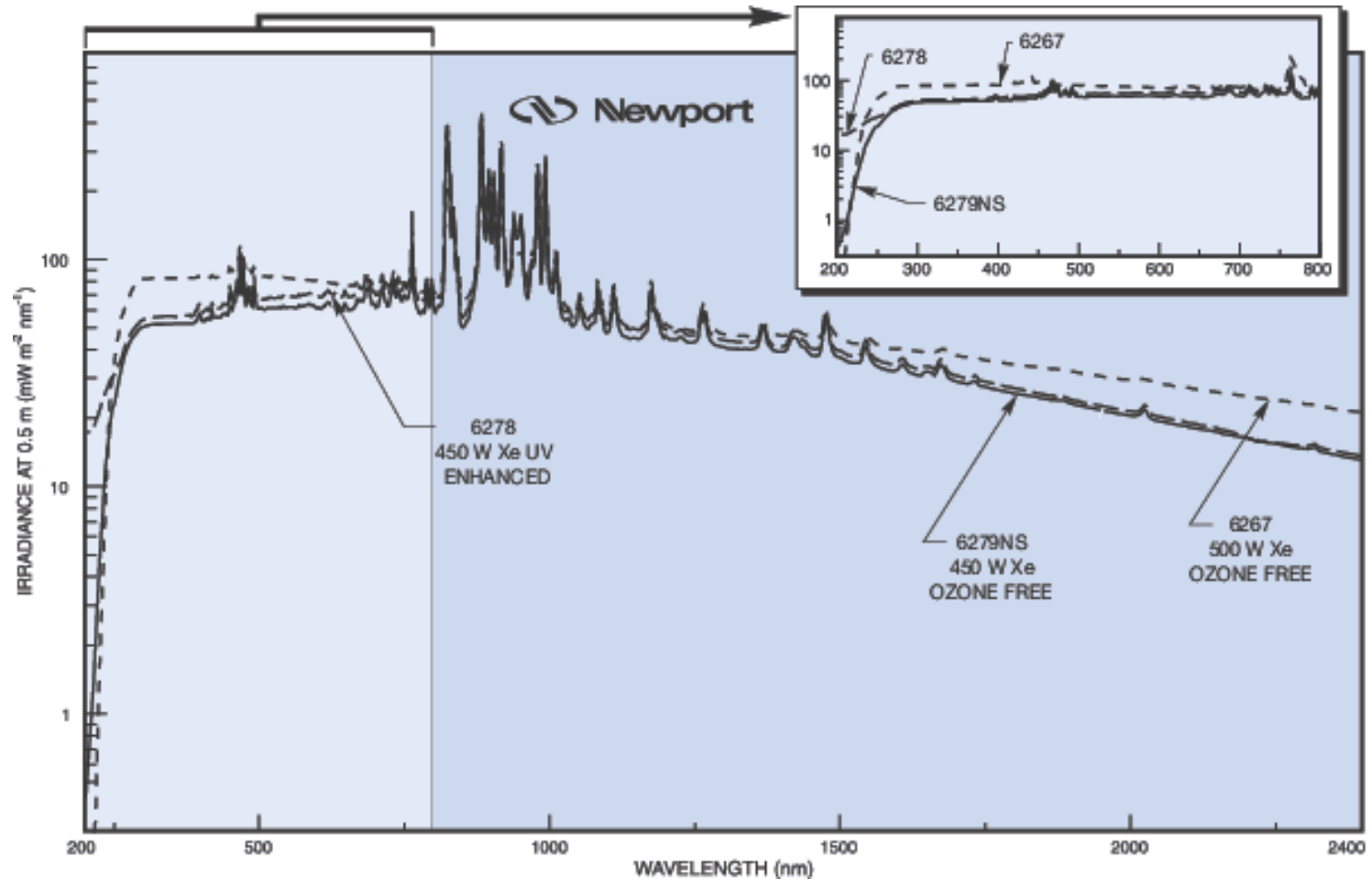
SPECTROFLUORIMETER

(Luminescence spectra)

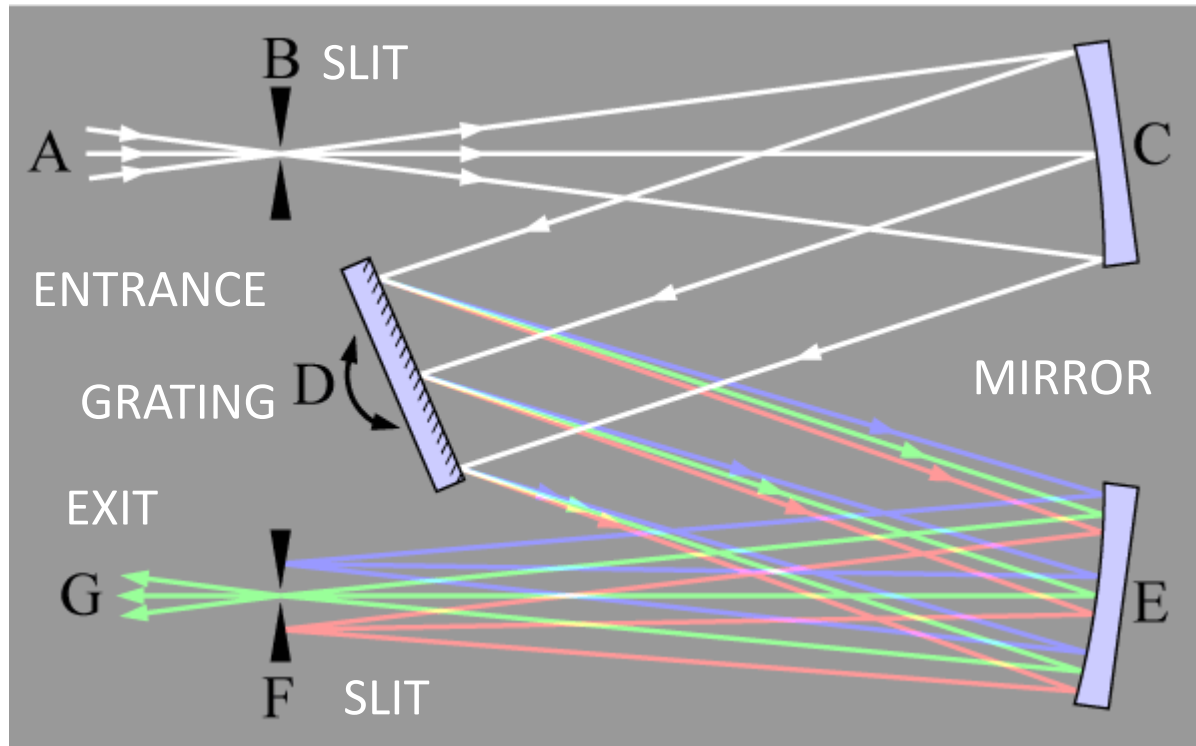


LIGHT SOURCE

Xe lamp (450W)



Monochromator

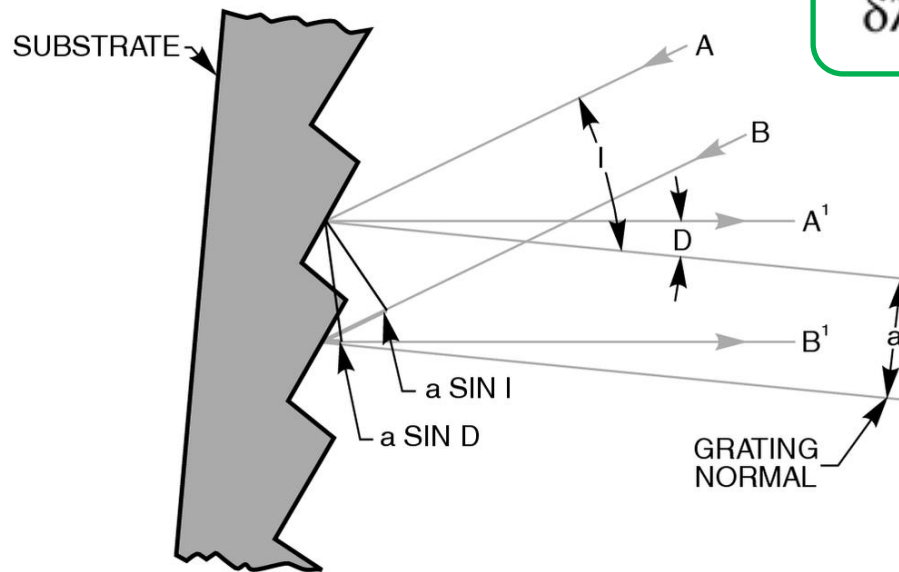


Grating: constructive interference

$$a(\sin I + \sin D) = m\lambda$$

dispersion

$$\frac{\delta D}{\delta \lambda} = \frac{m}{a \times \cos D}$$



a size of the reflecting element (groove)

m integer number indicating the order of interference

Grating: interferenza costruttiva

Alternative equation

$$m\lambda = 2 a \cos \phi \sin \theta$$

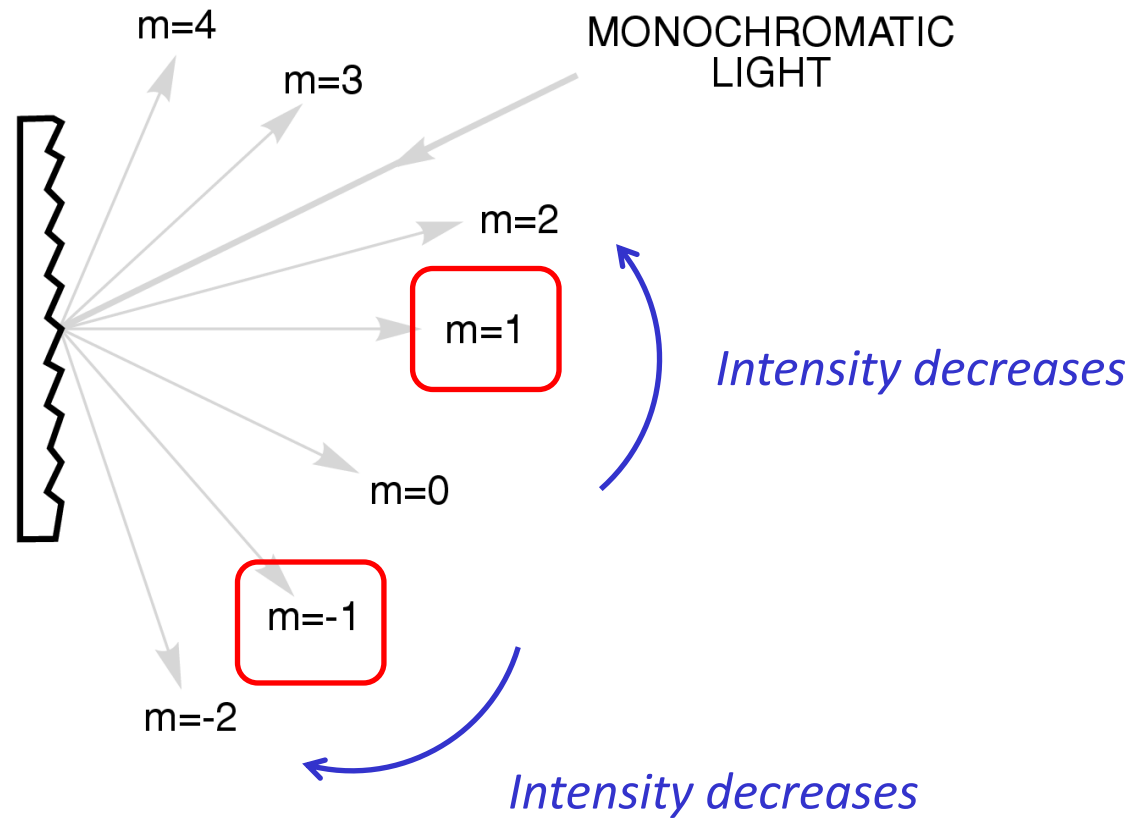
ϕ = Half the included angle between the incident ray and the diffracted ray at the grating

θ = Grating angle relative to the zero order position

$$I = \theta + \phi \text{ and } D = \theta - \phi$$

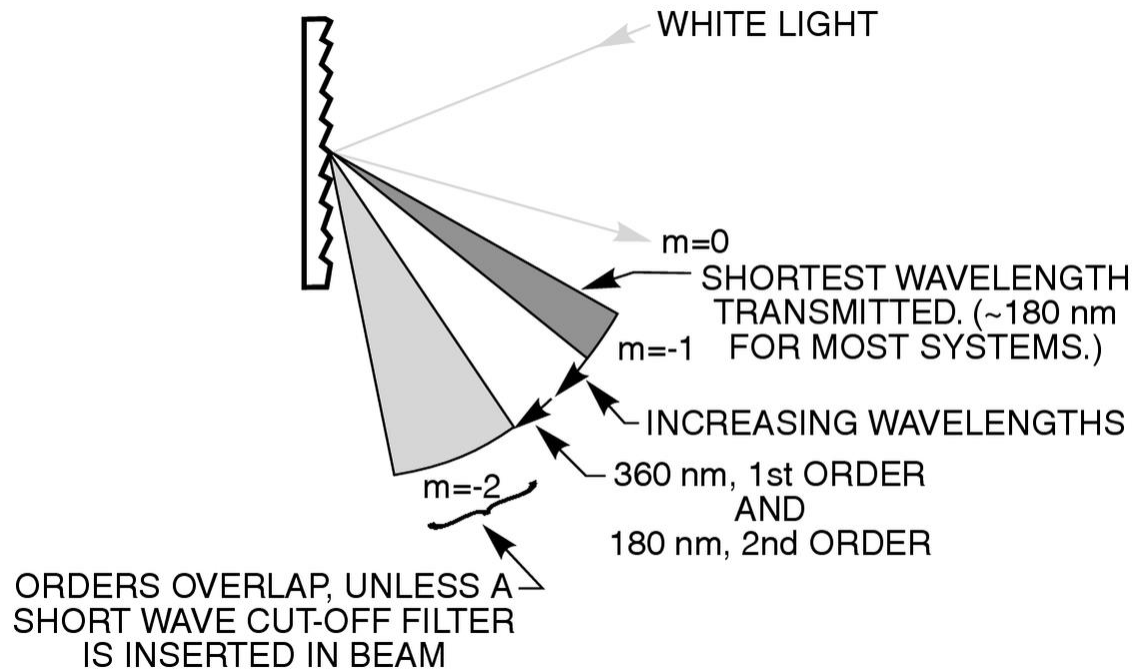
Grating: orders

$$a(\sin I + \sin D) = m\lambda$$

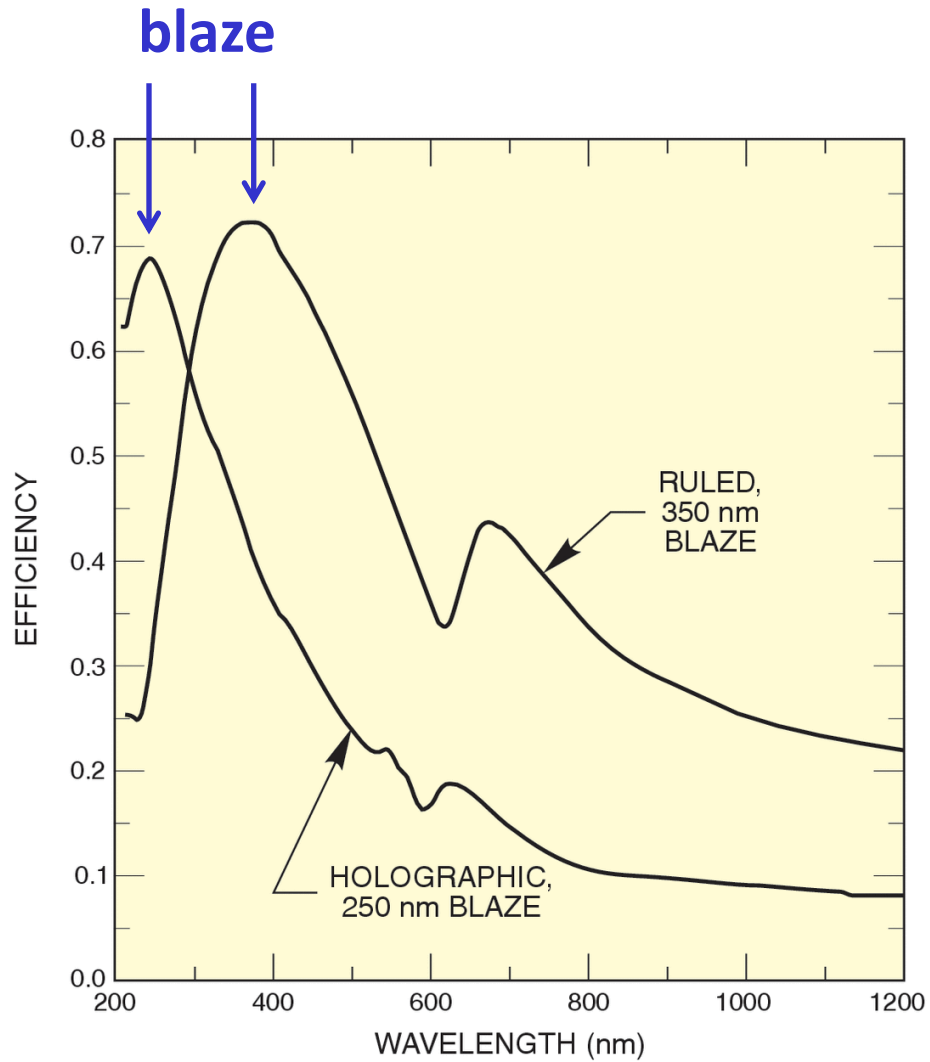


Grating: le armoniche

$$a(\sin I + \sin D) = m\lambda$$



Grating: spectral efficiency

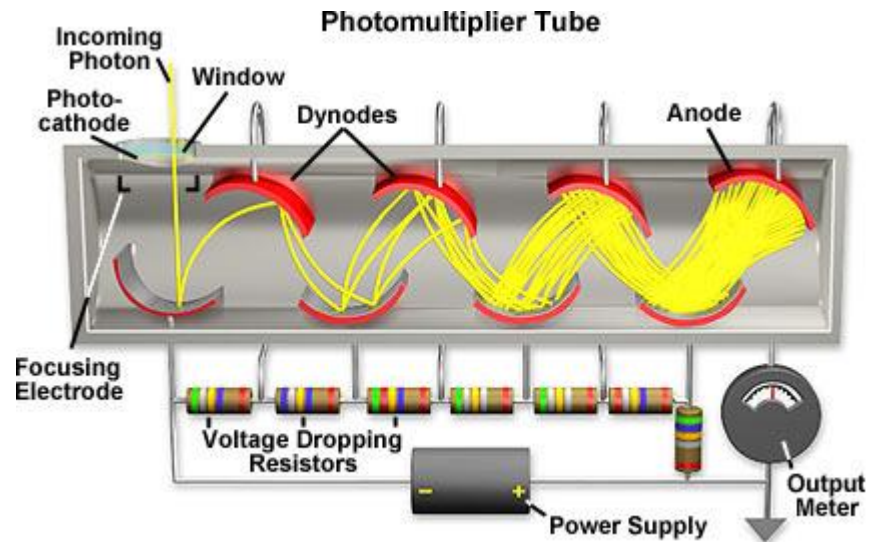
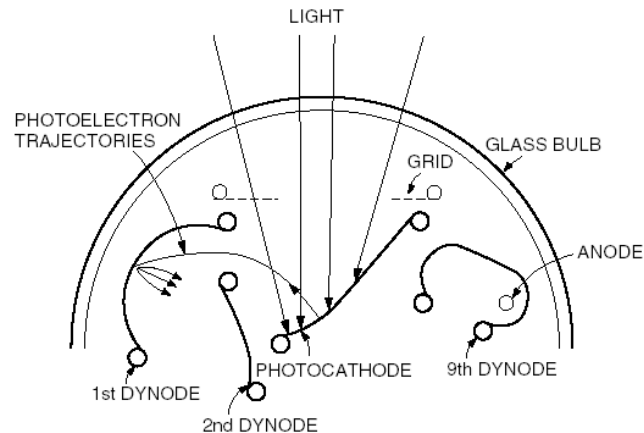


Detector: PhotoMultiplier Tube (PMT)

Hamamatsu R928



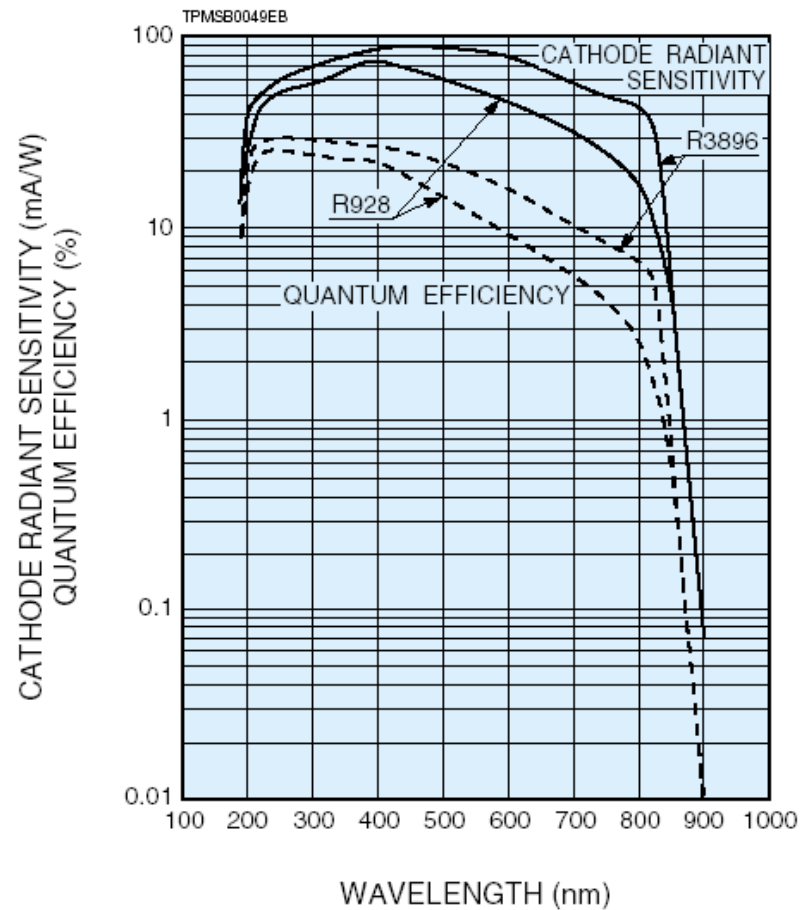
Figure 1: Electro Optical Structure



PhotoMultiplier Tube (PMT)

Spectral efficiency

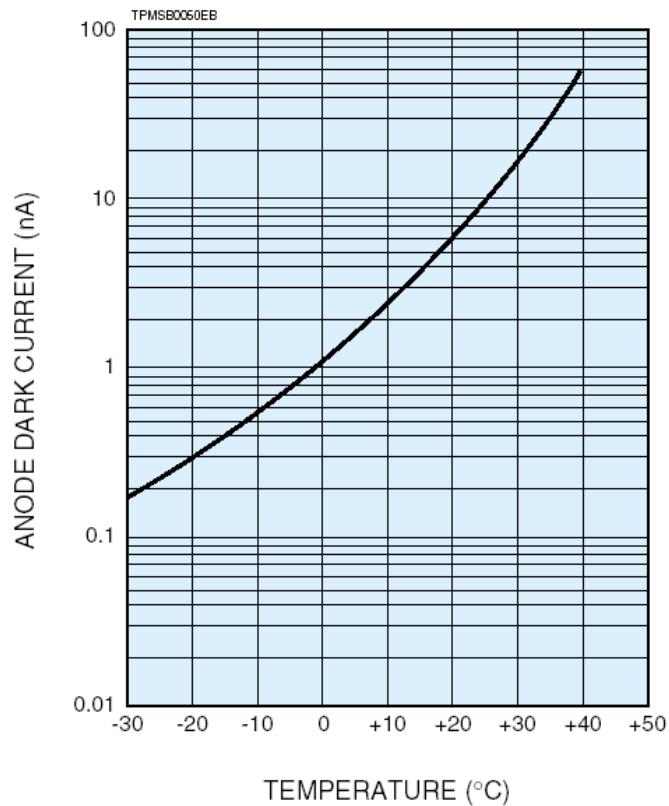
Figure 2: Typical Spectral Response



PhotoMultiplier Tube (PMT)

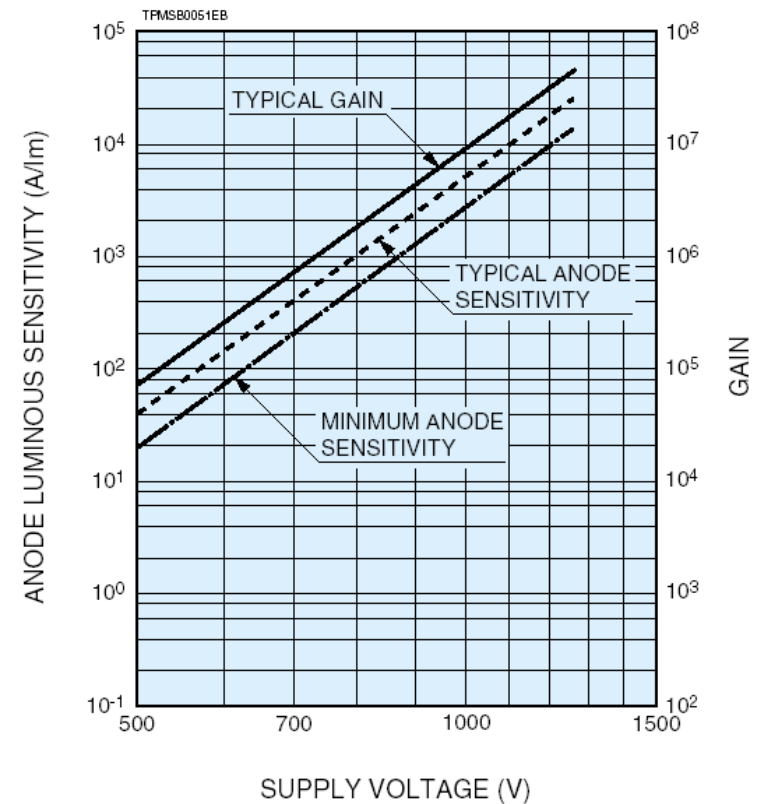
Dark current/Temperature

Figure 3: Typical Temperature Characteristics of Dark Current
(at 1000 V, after 30 min storage in darkness)

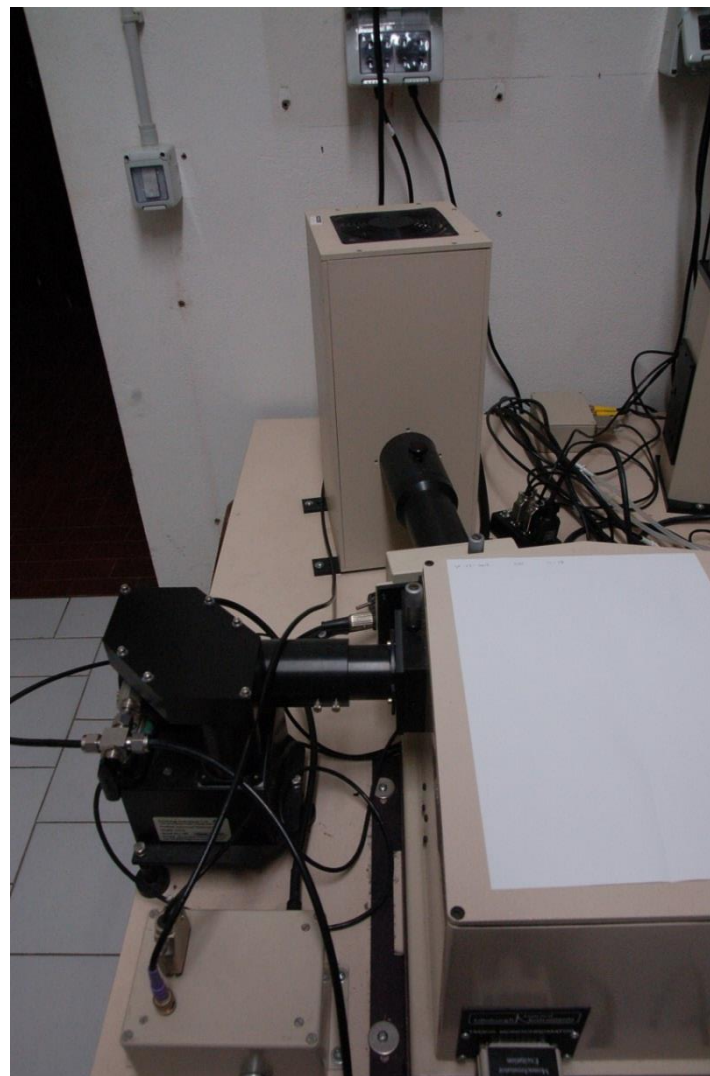


Signal/Voltage

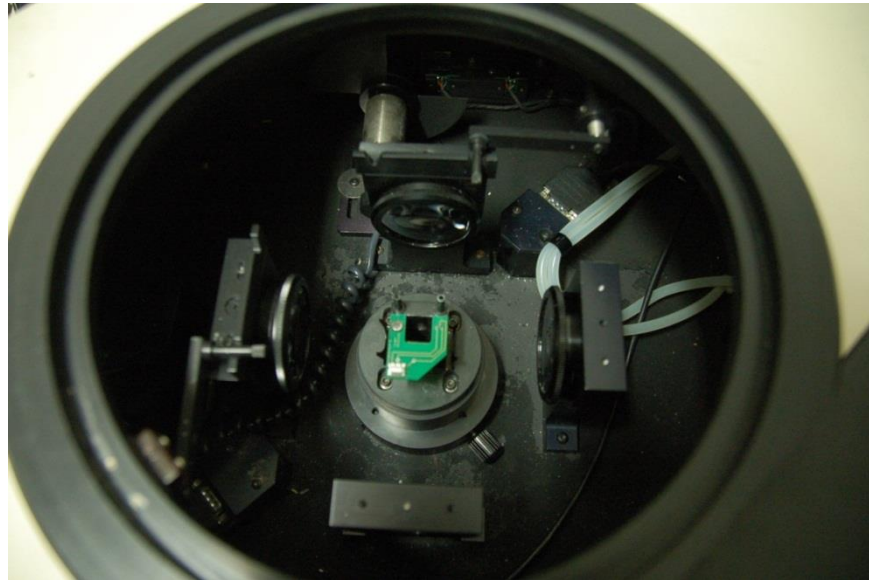
Figure 4: Anode Luminous Sensitivity and Gain Characteristics



Modular fluorimeter (FL920 Edinburgh)



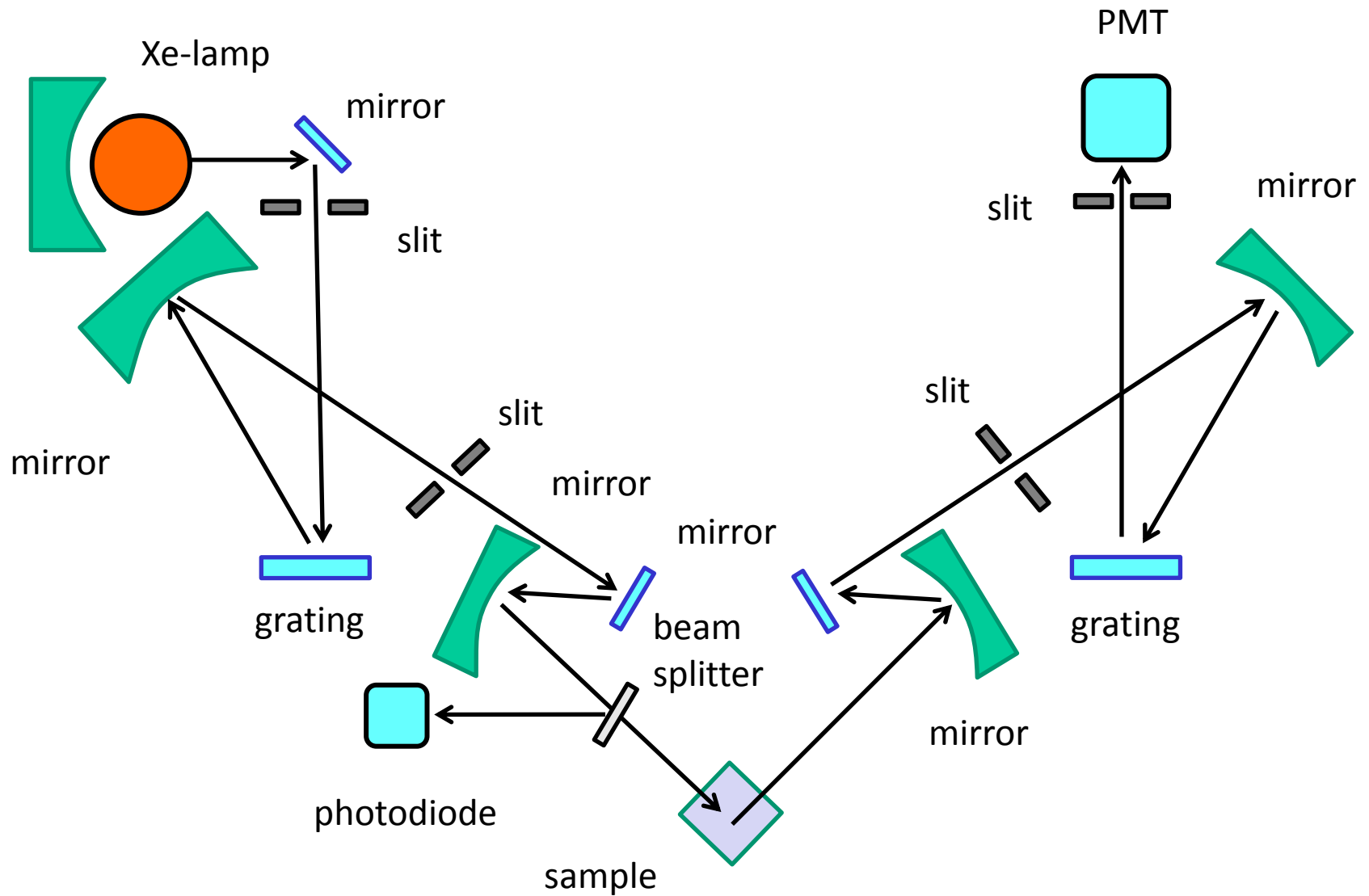
Modular fluorimeter (FL920 Edinburgh)



Compact fluorimeter (Perkin-Elmer LS 55)



Compact fluorimeter (Perkin-Elmer LS 55)



Parameters to be set (general)

Lamp Mode: fluorescence / phosphorescence

Built-in filters: Selection of the excitation / emission filters present inside the instrument

PMT voltage: from 650 to 900 volts.

By increasing the voltage sensitivity increases

If the voltage is too high, the system goes off the scale (saturation)

Parameters to be set (scanning)

mode: emission, excitation

λ excitation / emission: Depends on the properties of fluorophore

Spectral range: λ_{\max} , λ_{\min} in nm

based on the properties of fluorophore

Scan speed: in nm /min

Increasing the speed the resolution of the spectrum worsens

Increase the noise

For the same spectral range the acquisition time decreases

Parameters to be set (scanning)

Excitation slit: in nm

It is expressed as a passband

Increasing the slit the resolution of the spectrum of excitation decreases

By increasing the slit the measured signal does not change (in case of photodiode correction) but decreases the noise

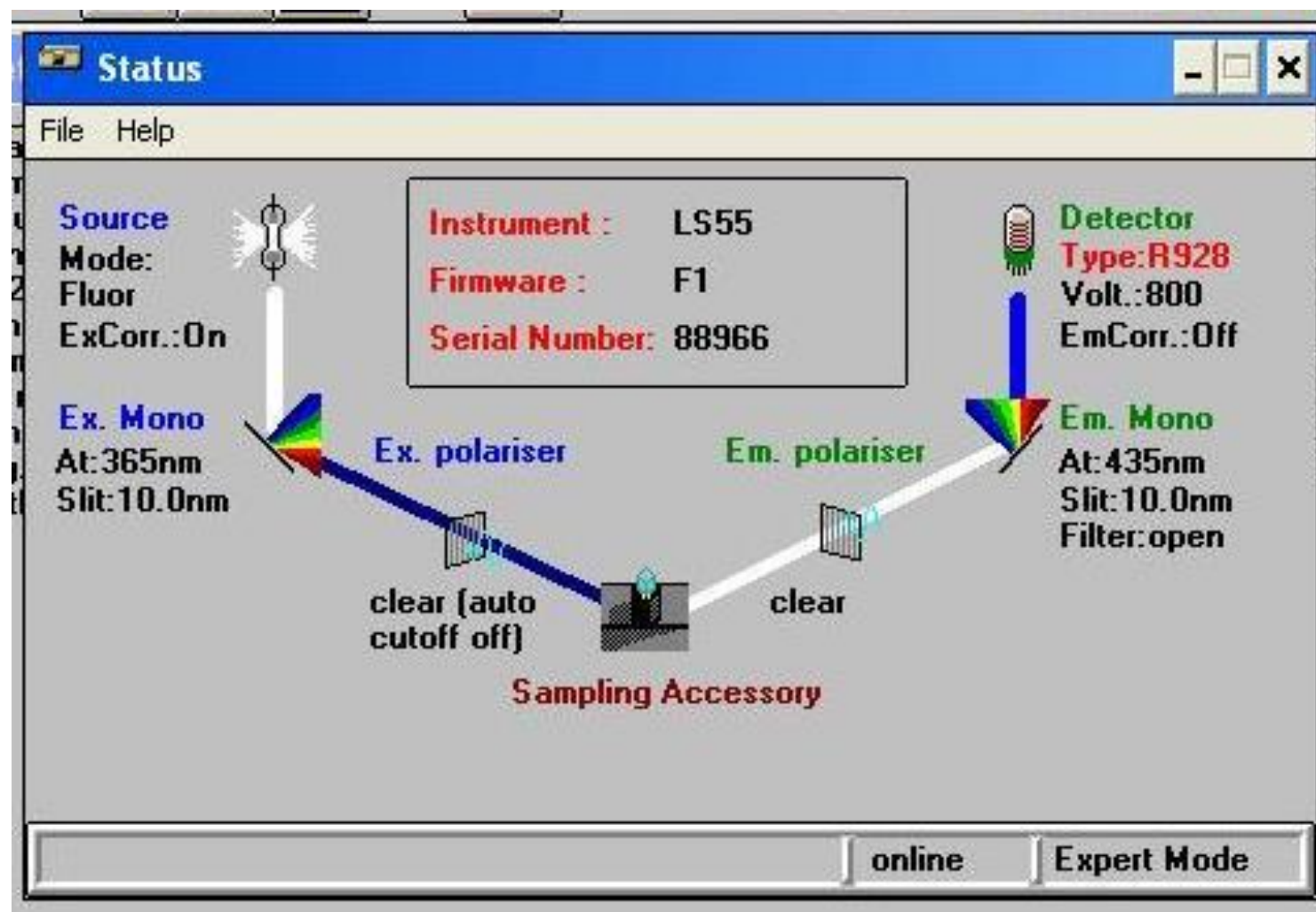
Emission slit: in nm

It is expressed as a passband

Increasing the slit the resolution of the emission spectrum decreases

By increasing the slit the signal increases





Scan: C:\FLWINLAB\METHODS\SCAN.MTH

File Instrument Help



Setup parameters

Realtime options

User info

View results

Excitation

Emission

Synchronous $\delta\lambda$ Synchronous δE

Pre-Scan

Scan Range Parameters

Start (nm): 600 End (nm): 850 Excitation (nm): 532

Ex Slit (nm): 10.0 Em Slit (nm): 2.5 Scan Speed (nm/min): 100

Result Filename:

emi-rb2.sp

☒ Auto increment filenames

Setting up instrument...






online

Expert Mode

ion method

Scan: C:\FLWINLAB\METHODS\SCAN.MTH

FileInstrumentHelp



Setup parametersRealtime optionsUser infoView results

ExcitationEmissionSynchronous $\delta\lambda$ Synchronous δE Pre-Scan

Scan Range Parameters

Start (nm): 600End (nm): 850Emission (nm): 330

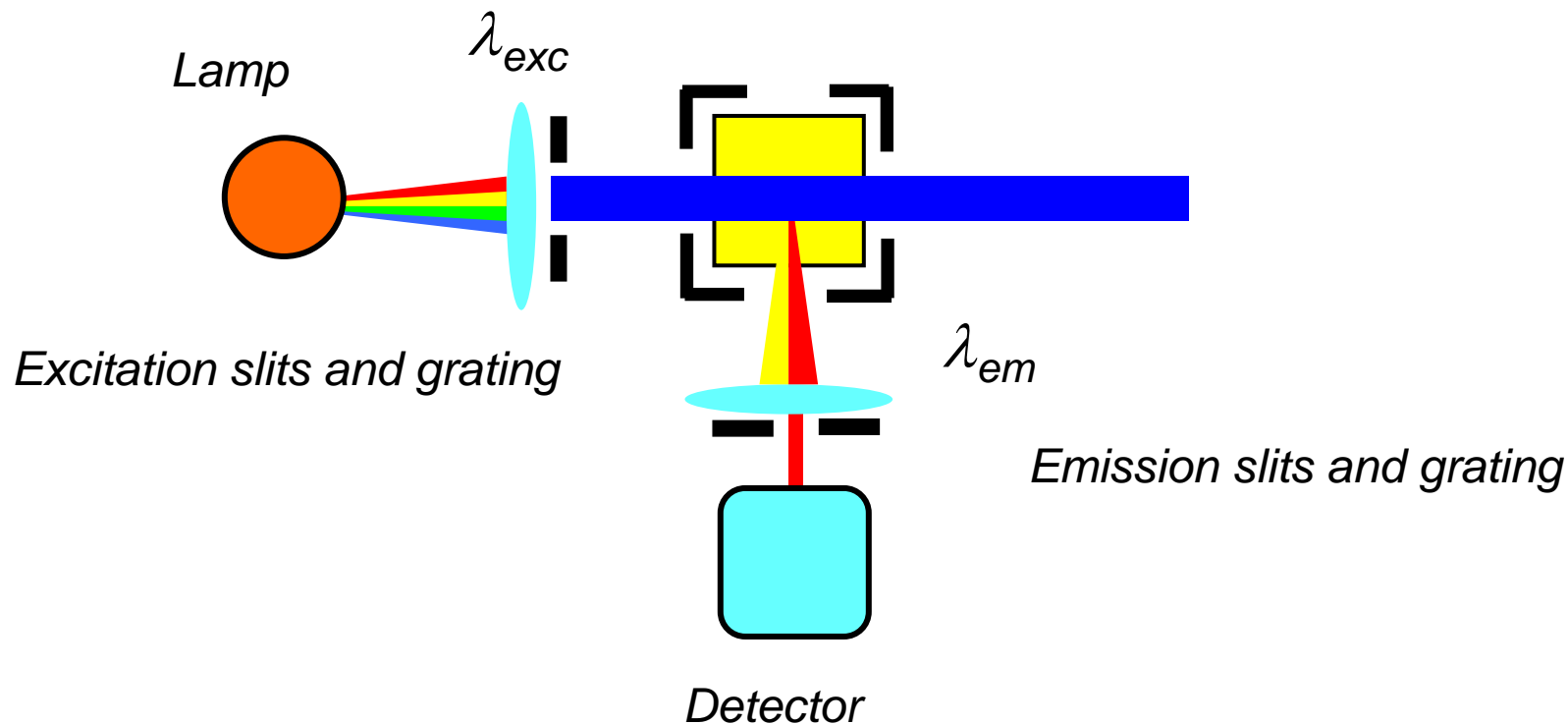
Ex Slit (nm): 10.0Em Slit (nm): 2.5Scan Speed (nm/min): 100

Result Filename:
emi-rb2.sp
☒ Auto increment filenames

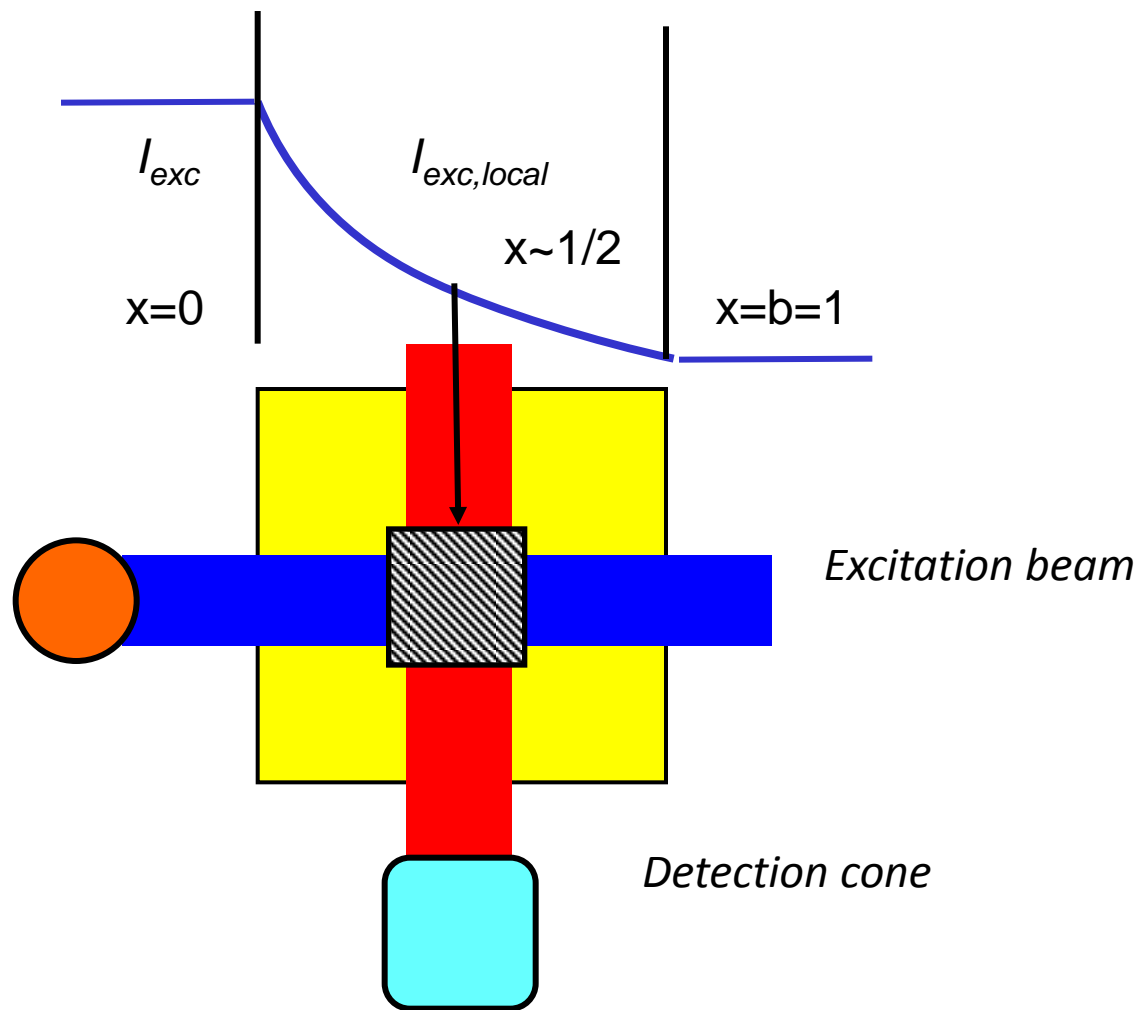
onlineExpert Mode

Dependency of the intensity on concentration

Masks are used in order to minimize scattering from the cuvette corners. Emission is detected at 90° with respect to excitation focussing on the center of the cuvette.



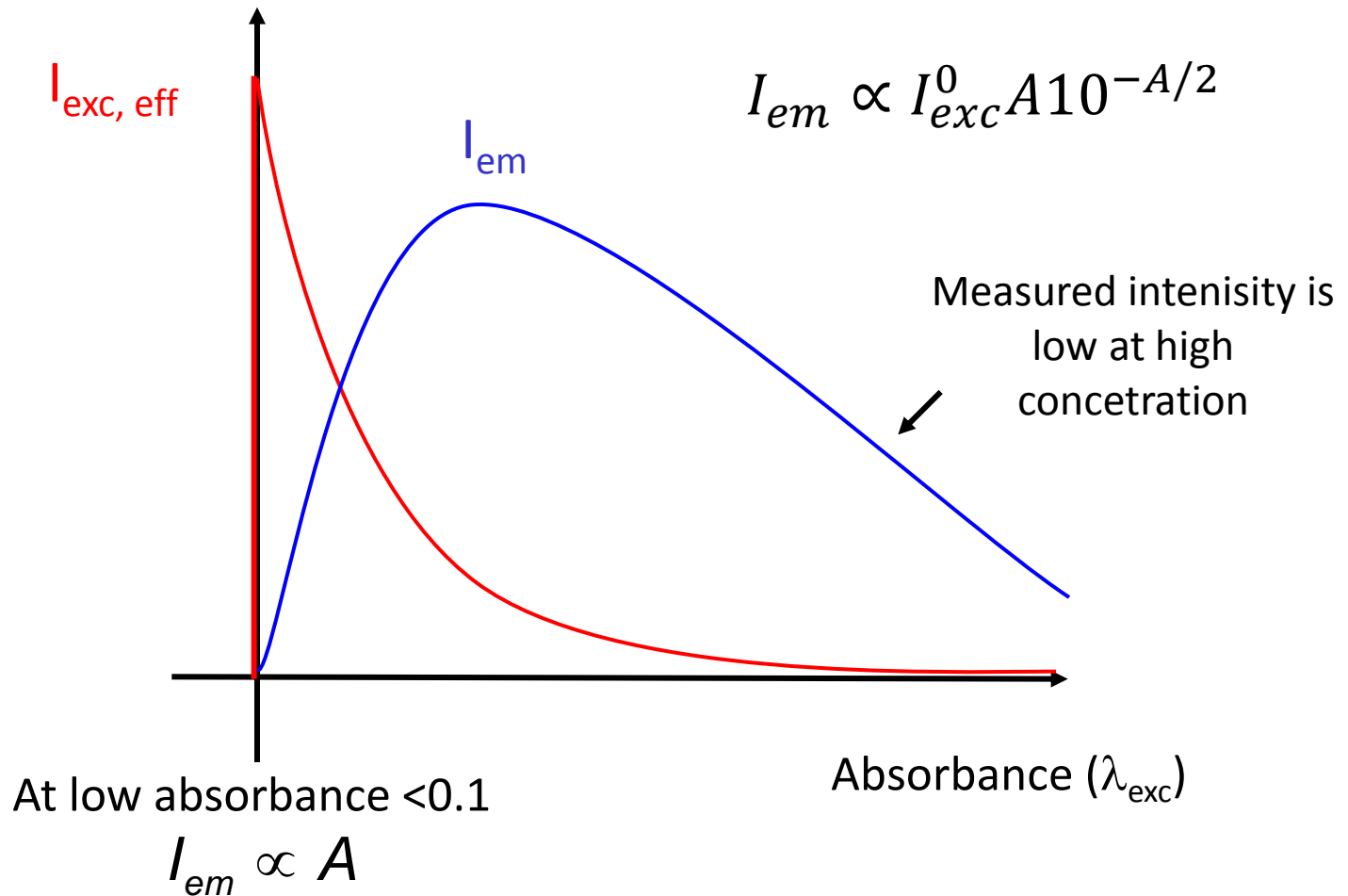
Dependency of the intensity on concentration



$$I_{exc}(x) = I_{exc}^0 10^{-Ax}$$

$$d[A^*] \propto -dI_{exc}(x) \propto I_{exc}^0 A 10^{-Ax}$$

Dependency of the intensity on concentration



Correction of fluorescence will be treated in detail by Prof. Silvi